MOSFET – Power, Dual, N-Channel, Power Clip, Trench, Asymmetric 30 V

NTMFD001N03P9

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

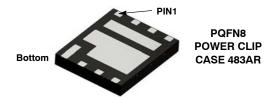
- DC-DC Converters
- System Voltage Rails



ON Semiconductor®

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FET	V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
Q1	30 V	5.0 mΩ @ 10 V	57 A
Qı	30 V	6.5 mΩ @ 4.5 V	37 A
Q2	30 V	1.0 mΩ @ 10 V	165 A
Q2	30 V	1.2 mΩ @ 4.5 V	105 A

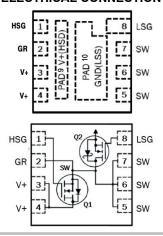


MARKING DIAGRAM

\$Y&Z&3&K 39HN

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code &K = Lot Code 39HN = Specific Device Code

ELECTRICAL CONNECTION



ORDERING INFORMATION

See detailed ordering and shipping information on page 10 of this data sheet.

Table 1. MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter				Q1	Q2	Unit
Drain-to-Source Voltage	V_{DSS}	30	30	V		
Gate-to-Source Voltage				±20	+16 V -12 V	V
Continuous Drain Current R _{0JC} (Note 3)	Steady State	T _C = 25°C	I _D	57	165	Α
		T _C = 85°C		41	119	
Power Dissipation $R_{\theta JC}$ (Note 3)		T _C = 25°C	P_{D}	25	41	W
Continuous Drain Current R _{0JA} (Note 1, 3)	Steady State	T _A = 25°C	I _D	16	38	Α
		T _A = 85°C		12	27	
Power Dissipation R _{0JA} (Note 1, 3)		T _A = 25°C	P_{D}	2.1	2.3	W
Continuous Drain Current R _{0JA} (Note 2, 3)	Steady State	T _A = 25°C	I _D	11	25	Α
		T _A = 85°C		8	18	
Power Dissipation R _{0JA} (Note 2, 3)		T _A = 25°C	P_{D}	0.96	1.04	W
Pulsed Drain Current	T _A = 25°C,	t _p = 10 μs	I _{DM}	300	500	Α
Single Pulse Drain-to-Source Avalanche Energy Q1: $I_L = 5.3 A_{pk}$, $L = 3 mH$ (Note 4) Q2: $I_L = 8.35 A_{pk}$, $L = 3 mH$ (Note 4)	•		E _{AS}	42	104	mJ
Operating Junction and Storage Temperature				-55 to 150		°C
Lead Temperature Soldering Reflow for Soldering Purposes (1/8" from case for 10 s)			T _L	260		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Table 2. THERMAL RESISTANCE RATINGS

Parameter	Symbol	Q1 Max	Q2 Max	Units
Junction-to-Case - Steady State (Note 1, 3)	Rejc	5.0	3.0	°C/W
Junction-to-Ambient - Steady State (Note 1, 3)	RθJA	60	55	
Junction-to-Ambient - Steady State (Note 2, 3)	RθJA	130	120	

Surface-mounted on FR4 board using 1 in² pad size, 2 oz Cu pad.
 Surface-mounted on FR4 board using minimum pad size, 2 oz Cu pad.

^{3.} The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted. Actual continuous current will be limited by thermal & electro-mechanical application board design. $R_{\Theta CA}$ is determined

by the user's board design.

4. Q1 100% UIS tested at L = 0.1 mH, I_{AS} = 20 A. Q2 100% UIS tested at L = 0.1 mH, I_{AS} = 47 A.

Table 3. ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Test Condition	FET	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•		<u>.</u>		.1
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	Q1	30			V
		V _{GS} = 0 V, I _D = 1 mA	Q2	30			
Drain-to-Source Breakdown Voltage	V _{(BR)DSS} /	I _D = 250 μA, ref to 25°C	Q1		15		mV/°C
Temperature Coefficient	T _J	I _D = 50 mA, ref to 25°C	Q2		16		
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	Q1			1	μΑ
		$V_{DS} = 24 \text{ V}$	Q2			500	1
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = 20 \text{ V}$	Q1			100	nA
		$V_{DS} = 0 \text{ V}, V_{GS} = 16 \text{ V}$	Q2			100	
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$	Q1	1.0		3.0	V
		$V_{GS} = V_{DS}$, $I_D = 1 \text{ mA}$	Q2	1.0		3.0	
Threshold Temperature Coefficient	V _{GS(TH)}	$I_D = 250 \mu\text{A}$, ref to 25°C	Q1		-5		mV/°C
	/T _J	$I_D = 50 \text{ mA}, \text{ ref to } 25^{\circ}\text{C}$	Q2		-3		
Drain-to-Source On Resistance	R _{DS(on)}	$R_{DS(on)}$ $V_{GS} = 10 \text{ V}, I_D = 17 \text{ A}$			4.5	5.0	mΩ
		V _{GS} = 4.5 V, I _D = 14 A			5.4	6.5	
		V _{GS} = 10 V, I _D = 40 A	Q2		0.75	1.0	
		V _{GS} = 4.5 V, I _D = 37 A			0.9	1.2	
Forward Transconductance	9FS	$V_{DS} = 5 \text{ V}, I_{D} = 14 \text{ A}$	Q1		93		S
		$V_{DS} = 5 \text{ V}, I_{D} = 37 \text{ A}$	Q2		248		
Gate Resistance	R_{G}	T _A = 25°C	Q1		1		Ω
		1A - 23 O	Q2		1		
CHARGES & CAPACITANCES							
Input Capacitance	C _{ISS}		Q1		1224		pF
			Q2		6575		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, V _{DS} = 15 V,	Q1		397		pF
		f = 1 MHz	Q2		2086		
Reverse Capacitance	C _{RSS}		Q1		42		pF
			Q2		138		
Total Gate Charge	$Q_{G(TOT)}$		Q1		7.9		nC
		Q1: V _{GS} = 4.5 V,	Q2		43		
Gate-to-Drain Charge	Q_{GD}	$V_{DS} = 15 \text{ V}, I_{D} = 14 \text{ A}$	Q1		2.0		nC
		Q2: V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 37 A	Q2		9.5		
Gate-to-Source Charge	Q_{GS}	00 - 1, 10 -771	Q1		3.1		nC
			Q2		15.8		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_D = 1$	14 A Q1		17		nC
		$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_D = 30 \text{ V}$	37 A Q2		93		

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 6. Switching characteristics are independent of operating junction temperatures

Table 3. ELECTRICAL CHARACTERISTICS (T $_J$ = 25 $^{\circ}$ C unless otherwise stated)

Parameter	Symbol	Test Condition		FET	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS	6, VGS = 4.5 V (No	te 6)		•				
Turn-On Delay Time	t _{d(ON)}			Q1		36		ns
				Q2		12.6		
Rise Time	t _{r(ON)}	V _{GS} = 4	1.5 V	Q1		30.7		ns
		Q1: $I_D = 14 \text{ A}, V_{DD} = 15 \text{ V},$ $R_G = 6 \Omega$		Q2		21.5		1
Turn-Off Delay Time	t _{d(OFF)}	Q2: I _D = 37 A,	V _{DD} = 15 V,	Q1		64.7		ns
		R _G = 6	$\delta \Omega$	Q2		17.5		
Fall Time	t _f			Q1		23.5		ns
				Q2		7.3		
SWITCHING CHARACTERISTICS	6, VGS = 10 V (Note	e 6)						
Turn-On Delay Time	t _{d(ON)}			Q1		8.0		ns
				Q2		8.6		
Rise Time	t _{r(ON)}	V _{GS} =	10 V	Q1		2.0		ns
		Q1: I _D = 17 A, V _{DD} = 15 V,		Q2		18.2		
Turn-Off Delay Time	t _{d(OFF)}	<u> </u>	$R_G = 6 \Omega$ Q2: $I_D = 40 \text{ A}, V_{DD} = 15 \text{ V},$			23.5		ns
		$R_G = 6 \Omega$		Q2		4.5		
Fall Time	t _f			Q1		2.0		ns
				Q2		4.5		
SOURCE-TO-DRAIN DIODE CH	ARACTERISTICS							
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C	Q1		0.79	1.2	V
		I _S = 14 A	T _J = 125°C			0.66		
		V _{GS} = 0 V,	T _J = 25°C	Q2		0.77	1.2	
		I _S = 37 A	T _J = 125°C]		0.63		
Reverse Recovery Time	t _{RR}			Q1		23		ns
		$V_{GS} = 0 V$		Q2		4.6		
Reverse Recovery Charge	Q _{RR}	Q1: $I_S = 14 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$ Q2: $I_S = 37 \text{ A}$, $dI/dt = 240 \text{ A}/\mu\text{s}$		Q1		8.0		nC
				Q2		68.3		1

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 6. Switching characteristics are independent of operating junction temperatures

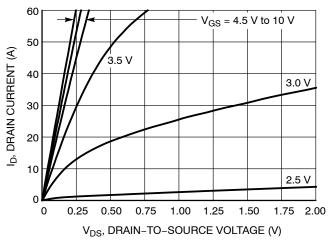


Figure 1. On-Region Characteristics

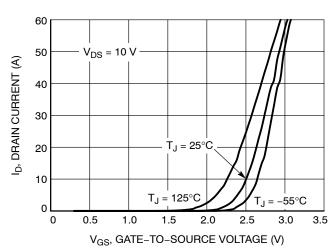


Figure 2. Transfer Characteristics

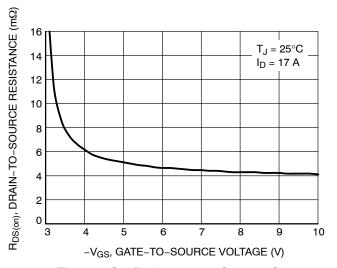


Figure 3. On-Resistance vs. Gate-to-Source Voltage

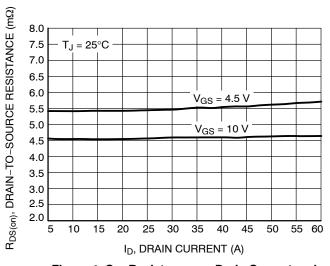


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

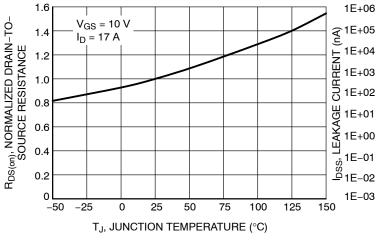


Figure 5. On–Resistance Variation with Temperature

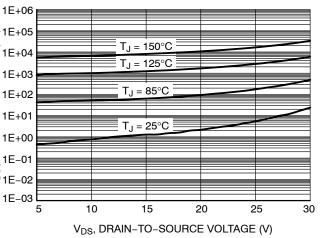


Figure 6. Drain-to-Source Leakage Current vs. Voltage

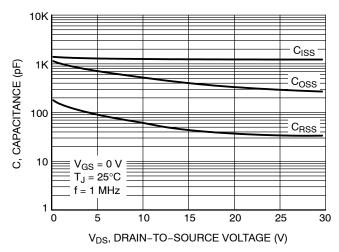


Figure 7. Capacitance Variation

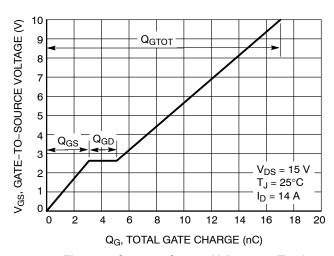
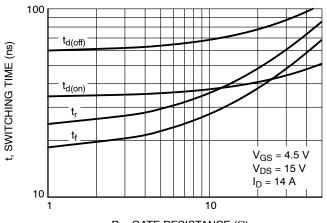


Figure 8. Gate-to-Source Voltage vs. Total Charge



 R_G , GATE RESISTANCE (Ω)

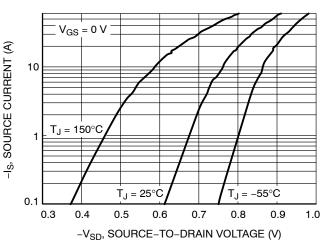


Figure 10. Diode Forward Voltage vs. Current



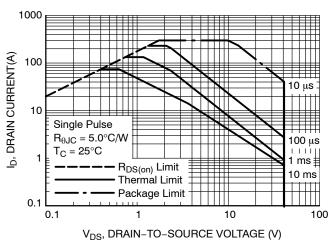


Figure 11. Maximum Rated Forward Biased Safe Operating Area

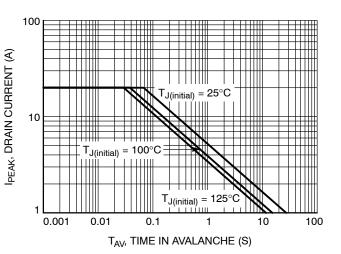


Figure 12. Maximum Drain Current vs. Time in Avalanche

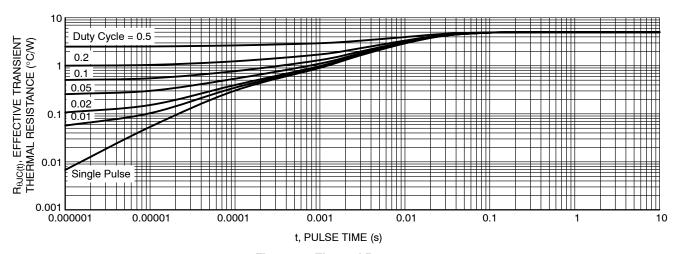


Figure 13. Thermal Response

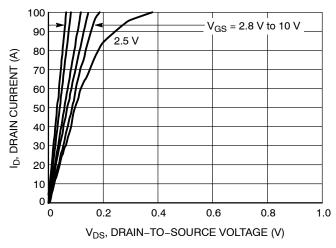


Figure 14. On-Region Characteristics

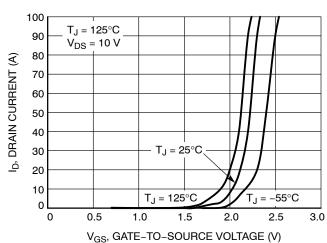


Figure 15. Transfer Characteristics

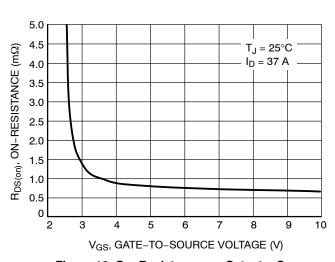


Figure 16. On-Resistance vs. Gate-to-Source Voltage

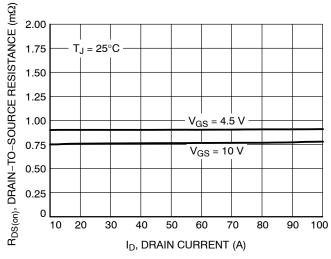


Figure 17. On-Resistance vs. Drain Current and Gate Voltage

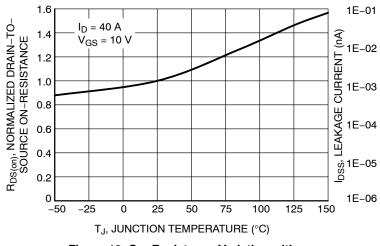


Figure 18. On-Resistance Variation with Temperature

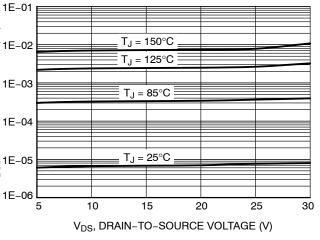


Figure 19. Drain-to-Source Leakage Current vs. Voltage

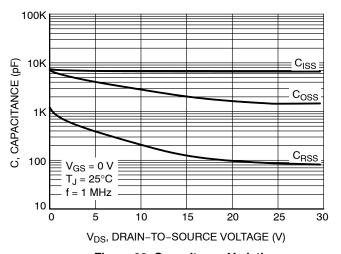


Figure 20. Capacitance Variation

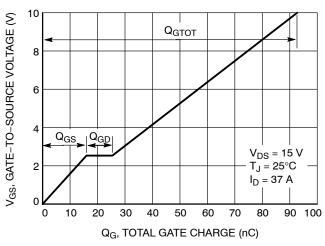


Figure 21. Gate-to-Source Voltage vs. Total Charge

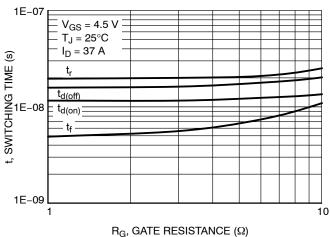


Figure 22. Resistive Switching Time Variation vs. Gate Resistance

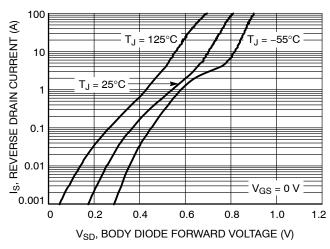


Figure 23. Diode Forward Voltage vs. Current

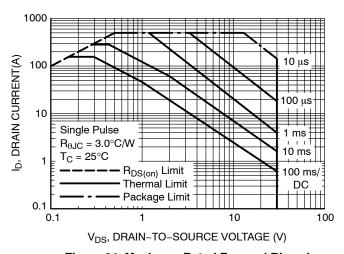


Figure 24. Maximum Rated Forward Biased Safe Operating Area

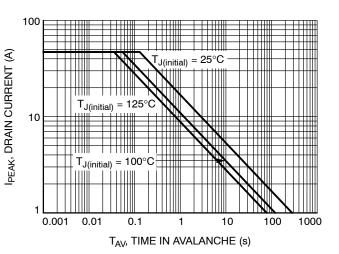


Figure 25. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS - Q2

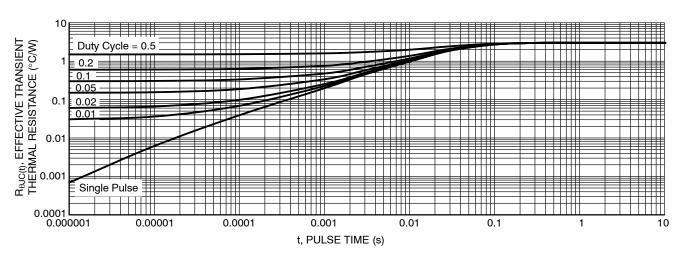


Figure 26. Transient Thermal Impedance

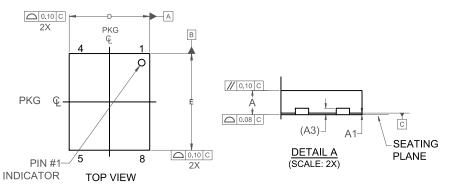
ORDERING INFORMATION

Device	Package	Shipping
NTMFD001N03P9	DFN8 (Pb-Free)	3000 / Tape & Reel



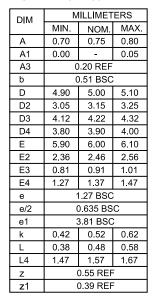
PQFN8 5x6, 1.27P CASE 483AR ISSUE A

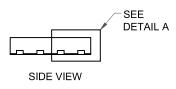
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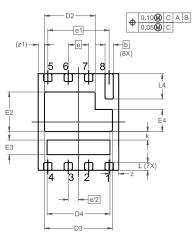


NOTES: UNLESS OTHERWISE SPECIFIED

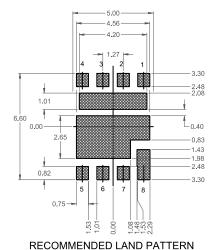
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- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.







BOTTOM VIEW



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MANUAL, SOLDERRM/D.

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